### **ESD Protection Diodes** Low Capacitance ESD Protection Diode for High Speed Data Line

## ESD8351, SZESD8351

The ESD8351 Series ESD protection diodes are designed to protect high speed data lines from ESD. Ultra-low capacitance and low ESD clamping voltage make this device an ideal solution for protecting voltage sensitive high speed data lines.

#### Features

- Low Capacitance (0.55 pF Max, I/O to GND)
- Protection for the Following IEC Standards: IEC 61000-4-2 (Level 4) ISO 10605
- Low ESD Clamping Voltage
- SZ Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC–Q101 Qualified and PPAP Capable
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

#### **Typical Applications**

- USB 2.0
- eSATA

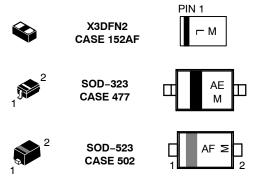
#### **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Operating Junction Temperature Range	TJ	-55 to +125	°C
Storage Temperature Range	T <sub>stg</sub>	-55 to +150	°C
Lead Solder Temperature – Maximum (10 Seconds)	ΤL	260	°C
IEC 61000-4-2 Contact (ESD) IEC 61000-4-2 Air (ESD) ISO 10605 330 pF / 2 kΩ Contact	ESD ESD ESD	±15 ±15 ±30	kV kV kV
Maximum Peak Pulse Current 8/20 μs @ T <sub>A</sub> = 25°C	I <sub>pp</sub>	5.0	A

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

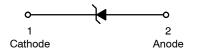
See Application Note AND8308/D for further description of survivability specs.

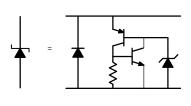












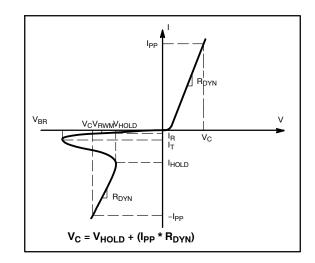
#### **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 6 of this data sheet.

#### **ELECTRICAL CHARACTERISTICS**

(T<sub>A</sub> = 25°C unless otherwise noted)

Symbol	Parameter
V <sub>RWM</sub>	Working Peak Voltage
I <sub>R</sub>	Maximum Reverse Leakage Current @ V <sub>RWM</sub>
V <sub>BR</sub>	Breakdown Voltage @ I <sub>T</sub>
Ι <sub>Τ</sub>	Test Current
V <sub>HOLD</sub>	Holding Reverse Voltage
I <sub>HOLD</sub>	Holding Reverse Current
R <sub>DYN</sub>	Dynamic Resistance
I <sub>PP</sub>	Maximum Peak Pulse Current
V <sub>C</sub>	Clamping Voltage @ I <sub>PP</sub> V <sub>C</sub> = V <sub>HOLD</sub> + (I <sub>PP</sub> * R <sub>DYN</sub> )



#### **ELECTRICAL CHARACTERISTICS** (T<sub>A</sub> = $25^{\circ}C$ unless otherwise specified)

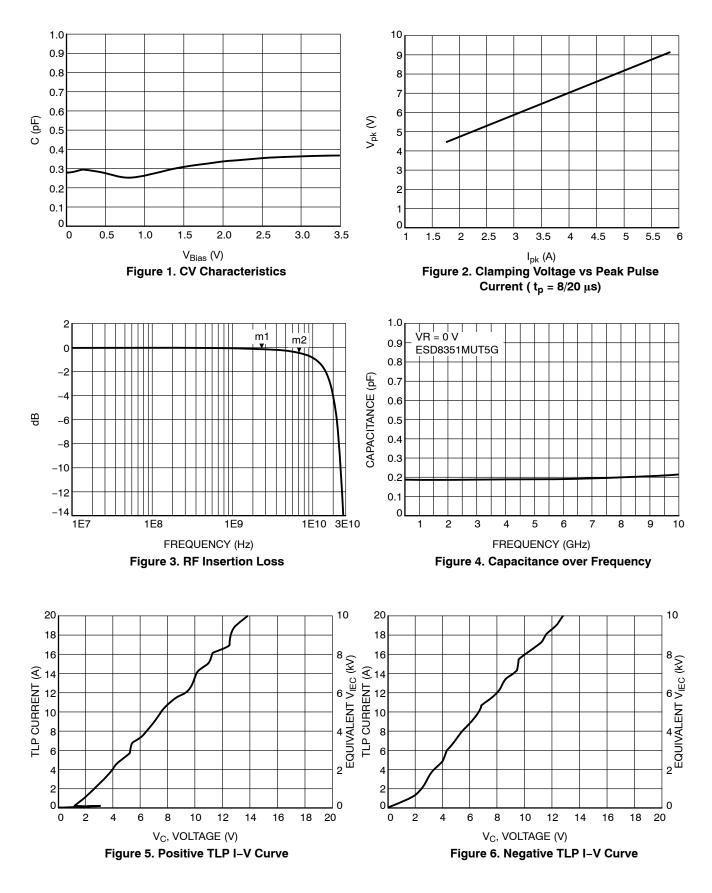
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Reverse Working Voltage	V <sub>RWM</sub>	I/O Pin to GND			3.3	V
Breakdown Voltage	V <sub>BR</sub>	I <sub>T</sub> = 1 mA, I/O Pin to GND	5.5	7.0	7.8	V
Reverse Leakage Current	I <sub>R</sub>	V <sub>RWM</sub> = 3.3 V, I/O Pin to GND			500	nA
Holding Reverse Voltage	V <sub>HOLD</sub>	I/O Pin to GND		1.15		V
Holding Reverse Current	I <sub>HOLD</sub>	I/O Pin to GND		20		mA
Clamping Voltage TLP (Note 2) See Figures 1 through 11	V <sub>C</sub>	$I_{PP} = 8 A $ $\begin{cases} IEC \ 61000-4-2 \ Level \ 2 \ equivalent \\ (\pm 4 \ kV \ Contact, \ \pm 4 \ kV \ Air) \end{cases}$		6.5		V
		$I_{PP} = 16 A \\ \begin{cases} IEC \ 61000-4-2 \ Level \ 4 \ equivalent \\ (\pm 8 \ kV \ Contact, \ \pm 15 \ kV \ Air) \end{cases}$		11.2		
Clamping Voltage (Note 3)	V <sub>C</sub>	$I_{PP} = 5 A$ $\begin{cases} t_p = 8 \times 20 \ \mu s \end{cases}$		8.2		V
Dynamic Resistance	R <sub>DYN</sub>	Pin1 to Pin2 Pin2 to Pin1		0.62 0.59		Ω
Junction Capacitance	CJ	$V_{R} = 0 V, f = 1 MHz$ ESD8351HT1G ESD8351XV2TxG ESD8351MUT5G $V_{R} = 0 V, f = 2.5 GHz$ ESD8351MUT5G		_ 0.40 0.40 0.25 _ 0.20	0.55 - - 0.45 -	pF

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 1. For test procedure see Figures 8 and 9 and application note AND8307/D.

ANSI/ESD STM5.5.1 – Electrostatic Discharge Sensitivity Testing using Transmission Line Pulse (TLP) Model. TLP conditions: Z<sub>0</sub> = 50 Ω, t<sub>p</sub> = 100 ns, t<sub>r</sub> = 4 ns, averaging window; t<sub>1</sub> = 30 ns to t<sub>2</sub> = 60 ns.
 Non-repetitive current pulse at T<sub>A</sub> = 20°C, per IEC 61000-4-5 waveform.

#### ESD8351, SZESD8351

#### **TYPICAL CHARACTERISTICS**



#### Latch–Up Considerations

**onsemi**'s 8000 series of ESD protection devices utilize a snap-back, SCR type structure. By using this technology, the potential for a latch-up condition was taken into account by performing load line analysis of common high speed serial interfaces. Example load lines for latch-up free applications and applications with the potential for latch-up are shown below with a generic IV characteristic of a snapback, SCR type structured device overlaid on each. In the latch-up free load line case, the IV characteristic of the snapback protection device intersects the load-line in one unique point (V<sub>OP</sub> I<sub>OP</sub>). This is the only stable operating

point of the circuit and the system is therefore latch-up free. In the non-latch up free load line case, the IV characteristic of the snapback protection device intersects the load-line in two points ( $V_{OPA}$ ,  $I_{OPA}$ ) and ( $V_{OPB}$ ,  $I_{OPB}$ ). Therefore in this case, the potential for latch-up exists if the system settles at ( $V_{OPB}$ ,  $I_{OPB}$ ) after a transient. Because of this, ESD8351 Series should not be used for HDMI applications – ESD8104 or ESD8040 have been designed to be acceptable for HDMI applications without latch-up. Please refer to Application Note AND9116/D for a more in-depth explanation of latch-up considerations using ESD8000 series devices.

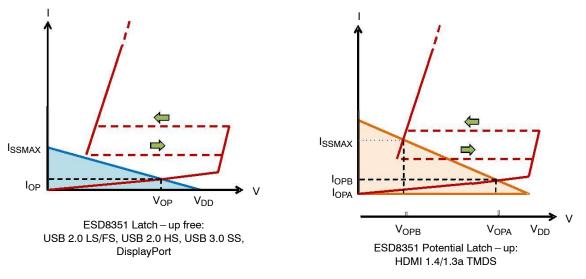


Figure 7. Example Load Lines for Latch-up Free Applications and Applications with the Potential for Latch-up

Application	VBR (min) (V)	IH (min) (mA)	VH (min) (V)	onsemi ESD8000 Series Recommended PN
HDMI 1.4/1.3a TMDS	3.465	54.78	1.0	ESD8104, ESD8040
USB 2.0 LS/FS	3.301	1.76	1.0	ESD8004, ESD8351
USB 2.0 HS	0.482	N/A	1.0	ESD8004, ESD8351
USB 3.0 SS	2.800	N/A	1.0	ESD8004, ESD8006, ESD8351
DisplayPort	3.600	25.00	1.0	ESD8004, ESD8006, ESD8351

#### ESD8351, SZESD8351

#### IEC 61000-4-2 Spec.

Level	Test Volt- age (kV)	First Peak Current (A)	Current at 30 ns (A)	Current at 60 ns (A)
1	2	7.5	4	2
2	4	15	8	4
3	6	22.5	12	6
4	8	30	16	8

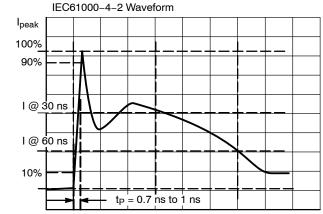


Figure 8. IEC61000-4-2 Spec

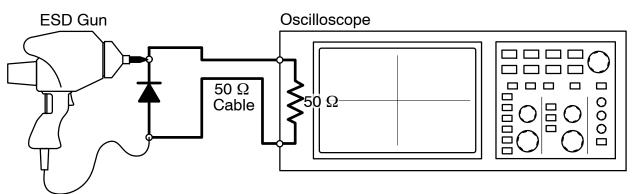


Figure 9. Diagram of ESD Clamping Voltage Test Setup

#### The following is taken from Application Note AND8308/D – Interpretation of Datasheet Parameters for ESD Devices.

#### **ESD Voltage Clamping**

For sensitive circuit elements it is important to limit the voltage that an IC will be exposed to during an ESD event to as low a voltage as possible. The ESD clamping voltage is the voltage drop across the ESD protection diode during an ESD event per the IEC61000–4–2 waveform. Since the IEC61000–4–2 was written as a pass/fail spec for larger

systems such as cell phones or laptop computers it is not clearly defined in the spec how to specify a clamping voltage at the device level. ON Semiconductor has developed a way to examine the entire voltage waveform across the ESD protection diode over the time domain of an ESD pulse in the form of an oscilloscope screenshot, which can be found on the datasheets for all ESD protection diodes. For more information on how ON Semiconductor creates these screenshots and how to interpret them please refer to AND8307/D.

#### Transmission Line Pulse (TLP) Measurement

Transmission Line Pulse (TLP) provides current versus voltage (I–V) curves in which each data point is obtained from a 100 ns long rectangular pulse from a charged transmission line. A simplified schematic of a typical TLP system is shown in Figure 10. TLP I–V curves of ESD protection devices accurately demonstrate the product's ESD capability because the 10s of amps current levels and under 100 ns time scale match those of an ESD event. This is illustrated in Figure 11 where an 8 kV IEC 61000–4–2 current waveform is compared with TLP current pulses at 8 A and 16 A. A TLP I–V curve shows the voltage at which the device turns on as well as how well the device clamps voltage over a range of current levels.

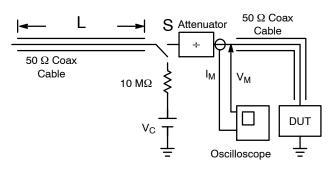


Figure 10. Simplified Schematic of a Typical TLP System

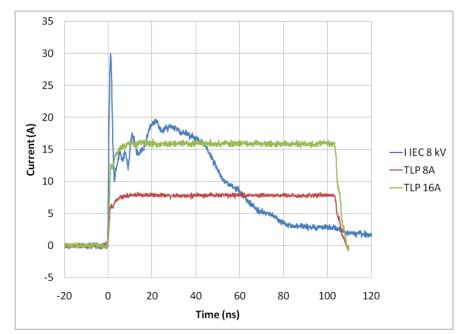


Figure 11. Comparison Between 8 kV IEC 61000-4-2 and 8 A and 16 A TLP Waveforms

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
ESD8351HT1G, SZESD8351HT1G*	SOD-323 (Pb-Free)	3000 / Tape & Reel
ESD8351XV2T1G, SZESD8351XV2T1G*	SOD-523	3000 / Tape & Reel
ESD8351XV2T5G, SZESD8351XV2T5G*	(Pb-Free)	8000 / Tape & Reel
ESD8351MUT5G	X3DFN2 (Pb–Free)	10000 / Tape & Reel
SZESD8351MUT5G*	X3DFN2 (Pb-Free)	15000 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

\*SZ Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable.

#### MECHANICAL CASE OUTLINE PACKAGE DIMENSIONS

# onsemi

CASE	<b>0.32x0.24, 0.35P</b> E 152AF SUE C			DAT	E 08 AUC	<del>3</del> 2023
	DTES: 1. DIMENSII ASME Y1 2. CONTROL 3. 0201	4.5M, 1	994,			
			MIL	LIMETER	22	]
		DIM	MIN.	N□M.	MAX.	1
INDICATOR (Optional) too (if)(		A	0.25	0.29	0.33	]
TOP VIEW		A1	0.00		0.05	
⊢A1		A2	0.14	0.24	0.34	
[//[0.05]C]		b	0.22	0.25	0.28	
		b2		0.150 RE	F	
		D	0.58	0.62	0.66	
		E	0.28	0.32	0.36	_
SIDE VIEW C		e		0.355 BS	SC	
SIDE VIEW		L2	0.17	0.20	0.23	_
e + + + + + + + + + + + + +		JNTING	MMEND	ED PRINT;	2X 30 * Pb-Free	e ownload ting
PIN 1 XM						

X = Specific Device Code M = Date Code

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

 
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 DESCRIPTION:
 X3DFN2 0.62x0.32x0.24, 0.35P
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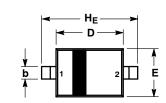
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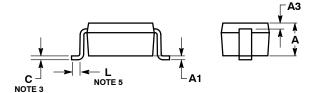
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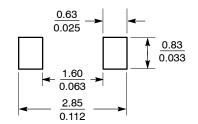


STYLE 1 SCALE 4:1





#### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

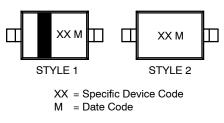
SOD-323 CASE 477-02 **ISSUE H** 

DATE 13 MAR 2007

- NOTES: 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: MILLIMETERS. 3. LEAD THICKNESS SPECIFIED PER L/F DRAWING WITH SOLDER PLATING. 1. DIMENSIONAL AND R. DO NOT INCLUSE MOLD.
- WITH SOLDER PLATING.
  4. DIMENSIONS A AND B DO NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS.
  5. DIMENSION L IS MEASURED FROM END OF RADIUS.

	MILLIMETERS				INCHES	6
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α	0.80	0.90	1.00	0.031	0.035	0.040
A1	0.00	0.05	0.10	0.000	0.002	0.004
A3	0.15 REF			0	.006 RE	F
b	0.25	0.32	0.4	0.010	0.012	0.016
С	0.089	0.12	0.177	0.003	0.005	0.007
D	1.60	1.70	1.80	0.062	0.066	0.070
Е	1.15	1.25	1.35	0.045	0.049	0.053
Г	0.08			0.003		
HE	2.30	2.50	2.70	0.090	0.098	0.105

#### GENERIC **MARKING DIAGRAM\***

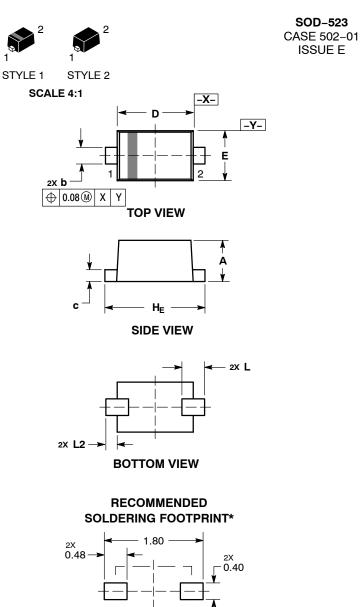


\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present.

STYLE 1: PIN 1. CATHODE (POLARITY BAND) 2. ANODE STYLE 2: NO POLARITY

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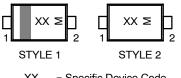
\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

DATE 28 SEP 2010

- NOTES: 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. 2. CONTROLLING DIMENSION: MILLIMETERS. 3. MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF PAREE MATERIAL
- BASE MATERIAL 4
- BASE MALENIAL. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PRO-TRUSIONS, OR GATE BURRS.

	MILLIMETERS						
DIM	MIN	MIN NOM MAX					
Α	0.50	0.60	0.70				
b	0.25	0.30	0.35				
с	0.07	0.14	0.20				
D	1.10	1.20	1.30				
Е	0.70	0.80	0.90				
ΗE	1.50	1.60	1.70				
L	0.30 REF						
L2	0.15	0.20	0.25				

#### GENERIC **MARKING DIAGRAM\***



XX = Specific Device Code Μ Date Code

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " .", may or may not be present.

STYLE 2: NO POLARITY STYLE 1: PIN 1. CATHODE (POLARITY BAND) 2. ANODE

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